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|-----------------------------------|--|-------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 09/910,709 | LEE ET AL. | |
| | | Examiner | Art Unit | Page 1 of 1 |
| | | Olisa Anwah | 2645 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-2002/0023099 | 02-2002 | Wendelrup, Heino | 707/200 |
| | B | US-2004/0110545 | 06-2004 | Kim, Ki ll | 455/575.1 |
| | C | US-2004/0092251 | 05-2004 | Fell et al. | 455/412.1 |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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